# TPS1120, TPS1120Y DUAL P-CHANNEL ENHANCEMENT-MODE MOSFETS

SLVS080A - MARCH 1994 - REVISED AUGUST 1995

Low r<sub>DS(on)</sub> . . . 0.18 Ω at V<sub>GS</sub> = -10 V

- 3-V Compatible
- Requires No External V<sub>CC</sub>
- TTL and CMOS Compatible Inputs
- $V_{GS(th)} = -1.5 \text{ V Max}$
- ESD Protection Up to 2 kV per MIL-STD-883C, Method 3015

# D PACKAGE (TOP VIEW) 1SOURCE [ 1 8 ] 1DRAIN 1GATE [ 2 7 ] 1DRAIN 2SOURCE [ 3 6 ] 2DRAIN 2GATE [ 4 5 ] 2DRAIN



#### description

The TPS1120 incorporates two independent p-channel enhancement-mode MOSFETs that have been optimized, by means of the Texas Instruments LinBiCMOS™ process, for 3-V or 5-V

power distribution in battery-powered systems. With a maximum  $V_{GS(th)}$  of -1.5 V and an  $I_{DSS}$  of only  $0.5\,\mu\text{A}$ , the TPS1120 is the ideal high-side switch for low-voltage portable battery-management systems, where maximizing battery life is a primary concern. Because portable equipment is potentially subject to electrostatic discharge (ESD), the MOSFETs have built-in circuitry for 2-kV ESD protection. End equipment for the TPS1120 includes notebook computers, personal digital assistants (PDAs), cellular telephones, bar-code scanners, and PCMCIA cards. For existing designs, the TPS1120D has a pinout common with other p-channel MOSFETs in small-outline integrated circuit SOIC packages.

The TPS1120 is characterized for an operating junction temperature range, T<sub>J</sub>, from −40°C to 150°C.

#### **AVAILABLE OPTIONS**

	PACKAGED DEVICEST	CHIP FORM
ТЈ	SMALL OUTLINE (D)	(Y)
-40°C to 150°C	TPS1120D	TPS1120Y

<sup>†</sup> The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS1120DR). The chip form is tested at 25°C.

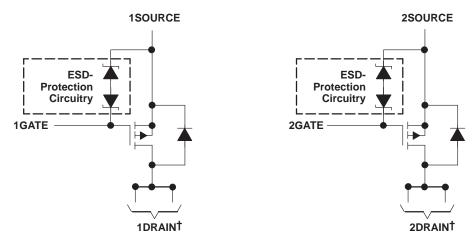


Caution. This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits.

LinBiCMS is a trademark of Texas Instruments Incorporated.



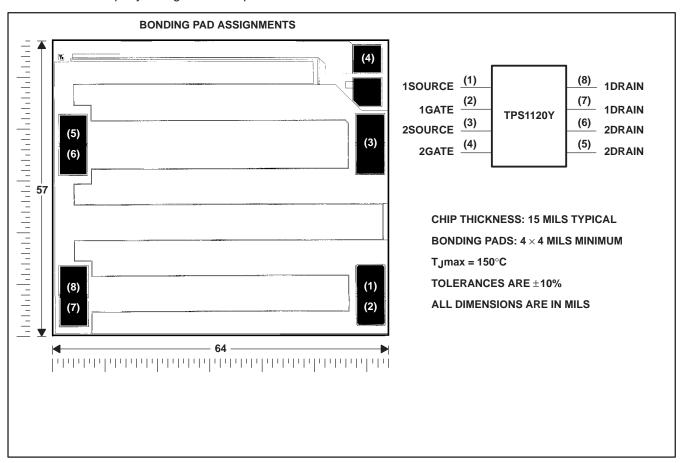
#### schematic



<sup>†</sup> For all applications, both drain pins for each device should be connected.

#### **TPS1120Y** chip information

This chip, when properly assembled, displays characteristics similar to the TPS1120C. Thermal compression or ultrasonic bonding may be used on the doped aluminum bonding pads. The chip may be mounted with conductive epoxy or a gold-silicon preform.



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#### absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

				UNIT		
Drain-to-source voltage, V <sub>DS</sub>	Drain-to-source voltage, VDS -15					
Gate-to-source voltage, VGS			2 or –15	V		
	V <sub>GS</sub> = -2.7 V	T <sub>A</sub> = 25°C	±0.39			
	VGS = -2.7 V	T <sub>A</sub> = 125°C	±0.21			
	V <sub>GS</sub> = -3 V	T <sub>A</sub> = 25°C	±0.5			
Continuous drain current, each device (T,J = 150°C), ID	VGS = -3 V	$T_A = 125^{\circ}C$	±0.25	A		
Continuous drain current, each device (1) = 130 C), iD	VGS = -4.5 V	T <sub>A</sub> = 25°C	±0.74	A		
	VGS = -4.5 V	T <sub>A</sub> = 125°C	±0.34			
	V <sub>GS</sub> = -10 V	T <sub>A</sub> = 25°C	±1.17			
		T <sub>A</sub> = 125°C	±0.53			
Pulse drain current, ID		T <sub>A</sub> = 25°C	±7	А		
Continuous source current (diode conduction), IS		T <sub>A</sub> = 25°C	-1	А		
Continuous total power dissipation		See Diss	ipation Rating	Table		
Storage temperature range, T <sub>Stg</sub>				°C		
Operating junction temperature range, T <sub>J</sub> -40 to				°C		
Operating free-air temperature range, T <sub>A</sub> -40 to 128				°C		
Lead temperature 1,6 mm (1/16 inch) from case for 10 second	onds		260	°C		

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{$A$}} \leq 25^{\circ}\mbox{$C$}$ POWER RATING	DERATING FACTOR <sup>‡</sup> ABOVE T <sub>A</sub> = 25°C			T <sub>A</sub> = 125°C POWER RATING
D	840 mW	6.71 mW/°C	538 mW	437 mW	169 mW

<sup>‡</sup> Maximum values are calculated using a derating factor based on R<sub>θJA</sub> = 149°C/W for the package. These devices are mounted on an FR4 board with no special thermal considerations.



#### TPS1120, TPS1120Y DUAL P-CHANNEL ENHANCEMENT-MODE MOSFETS

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#### electrical characteristics at $T_J = 25^{\circ}C$ (unless otherwise noted)

#### static

	PARAMETER	TEST CO	NDITIONS	٦	UNIT		
	PARAMETER	1231 00	MIN	TYP	MAX	UNIT	
VGS(th)	Gate-to-source threshold voltage	$V_{DS} = V_{GS}$	$I_D = -250 \mu\text{A}$	-1	-1.25	-1.50	V
V <sub>SD</sub>	Source-to-drain voltage (diode forward voltage) <sup>†</sup>	$I_{S} = -1 A$ ,	$V_{GS} = 0 V$		-0.9		V
IGSS	Reverse gate current, drain short circuited to source	$V_{DS} = 0 V$	$V_{GS} = -12 \text{ V}$			±100	nA
Inna	Zero-gate-voltage drain current	$V_{DS} = -12 V$ ,	$T_J = 25^{\circ}C$			-0.5	
IDSS	Zero-gate-voltage drain current	VGS = 0 V	T <sub>J</sub> = 125°C			-10	μΑ
		$V_{GS} = -10 \text{ V}$	$I_D = -1.5 A$		180		
r= o / \	Chatia duain to accuracy an atota majatanasa†	$V_{GS} = -4.5 \text{ V}$	$I_D = -0.5 A$		291	400	mΩ
rDS(on)	Static drain-to-source on-state resistance†	$V_{GS} = -3 V$	I <sub>D</sub> = -0.2 A		476	700	11152
		$V_{GS} = -2.7 \text{ V}$	] ID = -0.2 A		606	850	
9fs	Forward transconductance†	$V_{DS} = -10 V$ ,	$I_{D} = -2 \text{ A}$		2.5		S

<sup>†</sup> Pulse test: pulse width ≤ 300 μs, duty cycle ≤ 2%

#### static

	PARAMETER	TEST CO	NDITIONS	TF	UNIT		
	PARAIVIETER	lesi co	MIN	TYP	MAX	UNIT	
V <sub>GS(th)</sub>	Gate-to-source threshold voltage	$V_{DS} = V_{GS}$	$I_D = -250 \mu\text{A}$		-1.25		V
$V_{SD}$	Source-to-drain voltage (diode forward voltage)†	$I_{S} = -1 A$ ,	$V_{GS} = 0 V$		-0.9		V
		$V_{GS} = -10 \text{ V}$	$I_D = -1.5 A$		180		
 	Obatic ducto to account or state markets and	$V_{GS} = -4.5 \text{ V}$	$I_D = -0.5 A$		291		mΩ
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		$V_{GS} = -2.7 \text{ V}$	$I_D = -0.2 \text{ A}$		606		
9fs	Forward transconductance†	$V_{DS} = -10 \text{ V},$	$I_{D} = -2 A$		2.5		S

<sup>†</sup> Pulse test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%

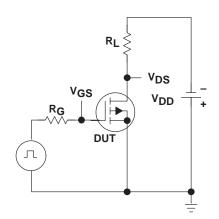
#### dynamic

	PARAMETER		TEST CONDITIONS				TPS1120, TPS1120Y			
	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT		
Qg	Total gate charge					5.45				
Qgs	Gate-to-source charge	$V_{DS} = -10 \text{ V},$	$V_{GS} = -10 V$ ,	$I_{D} = -1 A$		0.87		nC		
Q <sub>gd</sub>	Gate-to-drain charge	1				1.4				
td(on)	Turn-on delay time					4.5		ns		
td(off)	Turn-off delay time	$V_{DD} = -10 \text{ V},$	$R_L = 10 \Omega$ ,	$I_{D} = -1 A$ ,		13		ns		
t <sub>r</sub>	Rise time	$R_G = 6 \Omega$ ,	See Figures 1 and 2			10				
t <sub>f</sub>	Fall time					2		ns		
trr(SD)	Source-to-drain reverse recovery time	I <sub>F</sub> = 5.3 A,	di/dt = 100 A/μs			16				



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#### PARAMETER MEASUREMENT INFORMATION



**Figure 1. Switching-Time Test Circuit** 

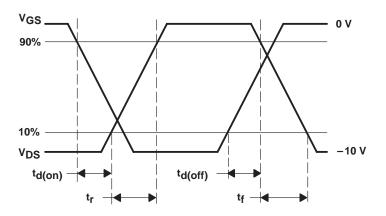
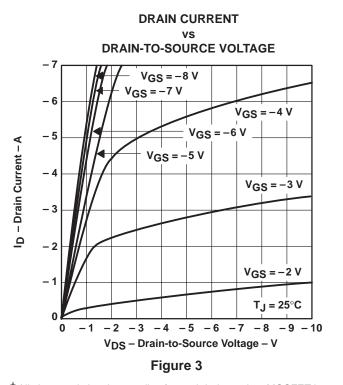


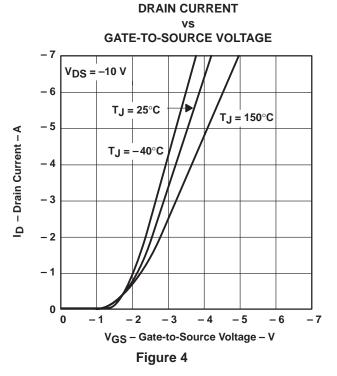
Figure 2. Switching-Time Waveforms

#### TYPICAL CHARACTERISTICS<sup>†</sup>

#### **Table of Graphs**

		FIGURE
Drain current	vs Drain-to-source voltage	3
Drain current	vs Gate-to-source voltage	4
Static drain-to-source on-state resistance	vs Drain current	5
Capacitance	vs Drain-to-source voltage	6
Static drain-to-source on-state resistance (normalized)	vs Junction temperature	7
Source-to-drain diode current	vs Source-to-drain voltage	8
Static drain-to-source on-state resistance	vs Gate-to-source voltage	9
Gate-to-source threshold voltage	vs Junction temperature	10
Gate-to-source voltage	vs Gate charge	11





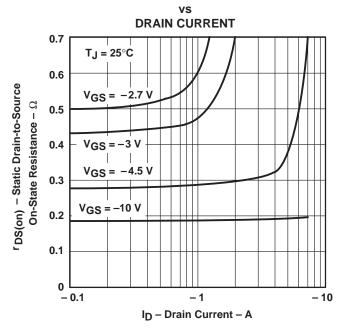
<sup>†</sup> All characteristics data applies for each independent MOSFET incorporated on the TPS1120.

**CAPACITANCE** 

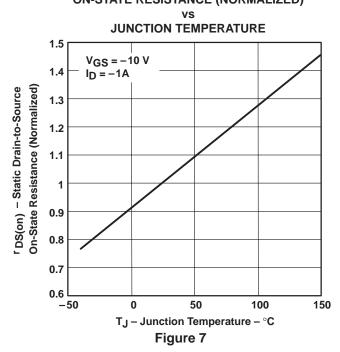
#### TYPICAL CHARACTERISTICS

50

#### STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE



## Figure 5 STATIC DRAIN-TO-SOURCE **ON-STATE RESISTANCE (NORMALIZED)**



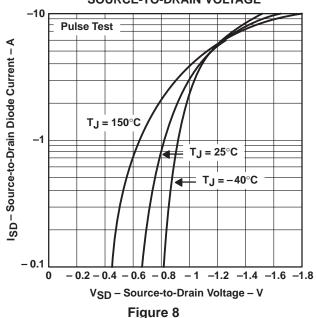
#### **DRAIN-TO-SOURCE VOLTAGE** 350 $V_{GS} = 0$ f = 1 MHz300 T<sub>J</sub> = 25°C C<sub>iss</sub>† 250 C - Capacitance - pF 200 Coss 150 100 c<sub>rss</sub>‡

V<sub>DS</sub> - Drain-to-Source Voltage - V  $\dagger C_{iss} = C_{gs} + C_{gd}, C_{ds(shorted)}$  $\ddagger C_{rss} = C_{gd}, C_{oss} = C_{ds} + \frac{C_{gs} C_{gd}}{C_{gs} + C_{gd}} \approx C_{ds} + C_{gd}$ Figure 6

-2 -3 -4 -5 -6 -7 -8 -9 -10 -11 -12

### SOURCE-TO-DRAIN DIODE CURRENT

**SOURCE-TO-DRAIN VOLTAGE** 



#### TYPICAL CHARACTERISTICS

#### STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

#### **GATE-TO-SOURCE VOLTAGE** 0.7 $I_D = -1 A$ <sup>r</sup>DS(on) - Static Drain-to-Source On-State T<sub>J</sub> = 25°C 0.6 0.5 Resistance $-\Omega$ 0.4 0.3 0.2 0.1 0 - 9 -13 - 15 - 1 V<sub>GS</sub> – Gate-to-Source Voltage – V

Figure 9

#### **GATE-TO-SOURCE THRESHOLD VOLTAGE**

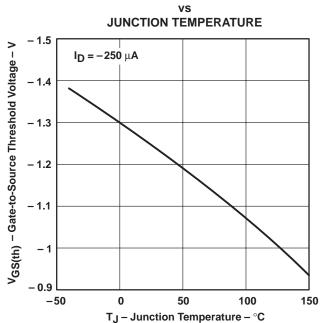


Figure 10

#### **GATE-TO-SOURCE VOLTAGE**

vs GATE CHARGE

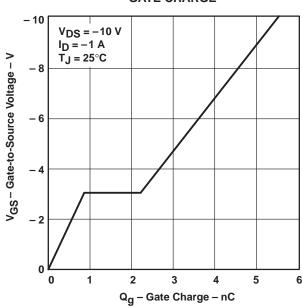
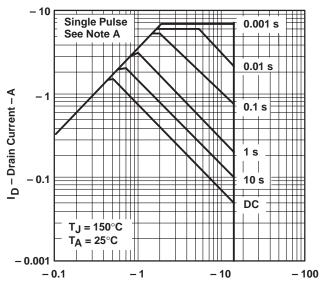


Figure 11



#### THERMAL INFORMATION

# DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE



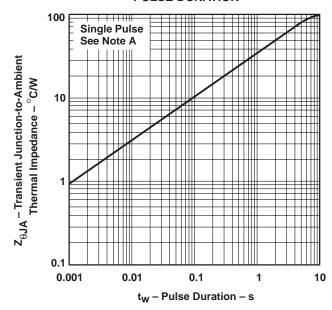
V<sub>DS</sub> - Drain-to-Source Voltage - V

NOTE A: FR4-board-mounted only

Figure 12

# TRANSIENT JUNCTION-TO-AMBIENT THERMAL IMPEDANCE

#### vs PULSE DURATION



NOTE A: FR4-board-mounted only

Figure 13



#### THERMAL INFORMATION

The profile of the heat sinks used for thermal measurements is shown in Figure 14. Board type is FR4 with 1-oz copper and 1-oz tin/lead (63/37) plate. Use of vias or through-holes to enhance thermal conduction was avoided.

Figure 15 shows a family of  $R_{\theta JA}$  curves. The  $R_{\theta JA}$  was obtained for various areas of heat sinks while subject to air flow. Power remained fixed at 0.25 W per device or 0.50 W per package. This testing was done at 25°C.

As Figure 14 illustrates, there are two separated heat sinks for each package. Each heat sink is coupled to the lead that is internally tied to a single MOSFET source and is half the total area, as shown in Figure 15. For example, if the total area shown in Figure 15 is 4 cm<sup>2</sup>, each heat sink is 2 cm<sup>2</sup>.

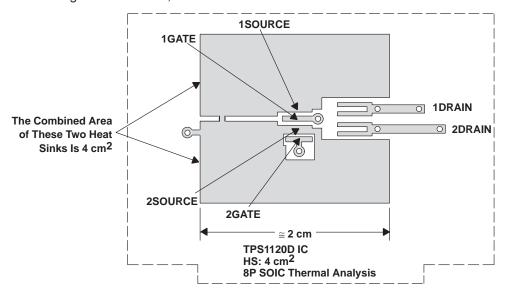


Figure 14. Profile of Heat Sinks

#### $\mathsf{R}_{\mathsf{ heta}\mathsf{JA}}$ – Thermal Resistance, Junction-to-Ambient – °C/W AIRFLOW, 25°C 150 0 cm<sup>2</sup> $T_{.1} = 25^{\circ}C$ 140 P = 0.5 W **Heat Sink Areas** 130 as Shown 0.5 cm<sup>2</sup> 120 1 cm<sup>2</sup> 110 100 90 80 70 2 cm<sup>2</sup> 8 cm<sup>2</sup> 60 4 cm<sup>2</sup> 50 50 100 150 200 250 300 Airflow, 25°C - ft/min

Figure 15

#### THERMAL INFORMATION

Figure 16 illustrates the thermally enhanced (SO) lead frame. Attaching the two MOSFET dies directly to the source terminals allows maximum heat transfer into a power plane.

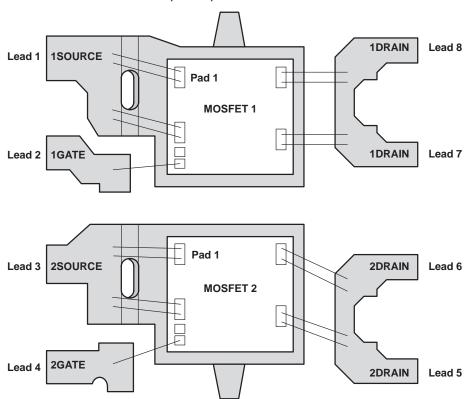


Figure 16. TPS1120 Dual MOSFET SO-8 Lead Frame

#### **APPLICATION INFORMATION**

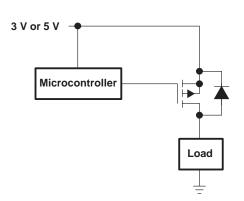


Figure 17. Notebook Load Management

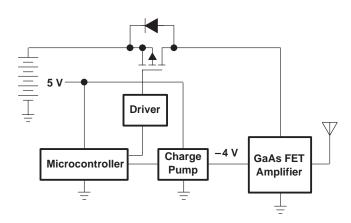


Figure 18. Cellular Phone Output Drive





i.com 17-Apr-2006

#### PACKAGING INFORMATION

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
TPS1120D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TPS1120DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TPS1120DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TPS1120DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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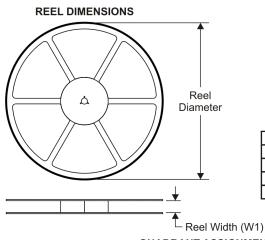
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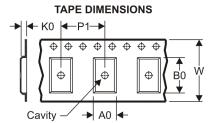




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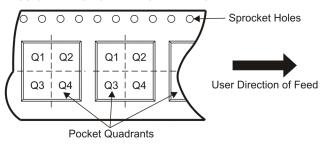
#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

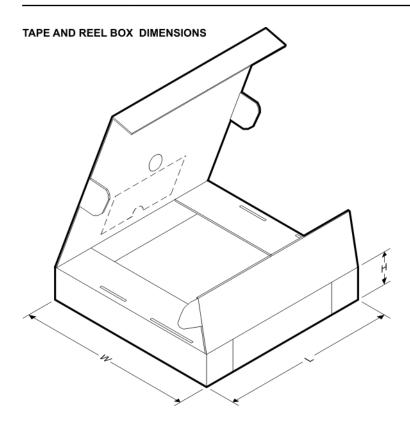


#### \*All dimensions are nominal

Device		Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS1120DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

#### PACKAGE MATERIALS INFORMATION

11-Mar-2008



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS1120DR	SOIC	D	8	2500	346.0	346.0	29.0

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